SERIAL NO. FORM PTO-1449 (Modified) ATTY. DOCKET NO. FIS9-2003-0238US1 10/707,842 LIST OF PATENTS AND PUBLICATION APPLICANT: APPLICANT'S INFORMATION DISCLOSURE Haining S. Yang, et al. **STATEMENT** FILING DATE: GROUP: (Use several sheets if necessary) Unassigned REFERENCE DESIGNATION **U.S. PATENT DOCUMENTS FILING DATE EXAMINER** DOCUMENT **CLASS SUBCLASS** (IF APPRO.) INITIALS NUMBER DATE NAME 5/8/2001 Doyle et al. 6,228,694 B1 6,406,973 B1 6/18/2002 Lee 8/28/2001 Doyle et al. 6,281,532 B1 5,683,934 11/4/97 Candelaria 4/9/2002 Kuhn, et al. 6,368,931 B1 5,310,446 5/10/94 Konishi et al. 4,853,076 8/1/89 Tsaur et al. US 2002/0090791 A1 7/11/2002 Doyle et al. US 2002/0074598 A1 6/20/2002 Doyle et al. 6,509,618 B2 of/21/2003 Jan et al. 6,476,462 B2 11/5/2002 Shimizu et al. 6,362,082 B1 3/26/2002 Doyle et al. 5,565,697 10/15/96 Asakawa et al. US 2003/0040158 A1 2/27/2003 Saitoh US 2002/0086472 A1 7/4/2002 Roberds et al. 6,521,964 B1 2/18/2003 Jan et al. 6,506,652 01/14/03 Jan, et al. FOREIGN PATENT DOCUMENTS TRANSLATION DOCUMENT DATE **COUNTRY CLASS** SUBCLASS NUMBER YES NO OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) EXAMINER DATE CONSIDERED EXAMINER: Initial if reference considered, whether of not citation is in conformance with MDEP 609. Draw line through citation if

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11/4	5,081,513	1/14/1992	Jackson, et al.	١ ١		1				
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	6,531,740	3/11/2003	Bosco, et al.							
414	6,531,369	3/11/2003	Ozkan, et al.	† †						
111	6,501,121	12/31/2002	Yu, et al.	1 1						
111	6,498,358	12/24/2002	Lach, et al.	1 1						
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1.4	6,255,169	7/3/2001	Li, et al.							
- Kal	6,246,095	6/12/2001	Brady, et al.	<del>                                     </del>	1 1					
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101	6,046,464	4/4/2000	Schetzina		<del>-                                    </del>					
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124	5,989,978	11/23/1999		Peidous		7						
W	6,284,626	9/4/2001		Kim					γγ			
WL	6,274,444	8/14/2001		Wang						:		
WL	6,261,964	7/17/2001		Wu, et al.								
WL	6,221,735	4/24/2001		Manley, et al.								
WL	6,117,722	9/12/2000		Wuu, et al.								
WL	6,107,143	8/22/2000		Park, et al.								
WL	6,090,684	7/18/2000		Ishitsuka, et al.								
WL	6,066,545	5/23/2000		Doshi, et al.					Ш			
WL	6,008,126	12/28/1999		Leedy					Ш			
WI	5,946,559	8/31/1999		Leedy					Ш_			
414	5,840,593	11/24/1998		Leedy			<u> </u>		Ш_			
W	5,592,018	1/7/1997		Leedy								
W	5,592,007	1/7/1997		Leedy								
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WC	International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.  Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs", 2002 Symposium On VLSI Technology Digest of Technical Papers, IEEE, pp 98-99.											
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